

Factory Witness

Characterization

Light-Induced Degradation

CID

LID

Characterization

Thermal Cycling	Damp Heat	Mechanical Stress Sequence	Potential-Induced Degradation	UVID Sensitivity	LETID Sensitivity	Hail Stress Sequence	PAN File & IAM Profile	Backsheet Durability Sequence
TC 200	DH 1000	SML (tracker or corner-mount)	85°C, 85%RH MSV (+ and/or -) 192 hrs	UV 60 kWh/m ² 60°C front	LETID 162 hrs 75°C, 2*(Isc-Imp)	Hail (two sizes)	PAN File	DH 200
Characterization	Characterization	Characterization	Characterization	Characterization	Characterization	Characterization	IAM Profile	Characterization
TC 200	DH 1000	DML1000		UV 60 kWh/m ² 60°C front	LETID 162 hrs 75°C, 2*(Isc-Imp)	DML 1000		UV 65 kWh/m ² 80°C rear
Characterization	Characterization	Characterization		Characterization	Characterization	Characterization		Characterization
TC 200		TC 50 + HF 10		Characterization	Characterization	TC 50 + HF 10		TC 50 + HF 10
Characterization		Characterization				Characterization		UV 65 kWh/m ²
								Characterization
								TC 50 + HF 10
								UV 65 kWh/m ²
								Characterization
								TC 50 + HF 10
								UV 6.5 kWh/m ²
								Characterization

OPTIONAL

Factory Witness

All Bills of Materials submitted for testing are witnessed in production from opening of raw materials packages through every step of the production process to final packaging with tamper-proof tape.

Testing Abbreviations

TC: Thermal cycling
 DH: Damp heat
 UV: Ultraviolet
 HF: Humidity freeze
 LETID: Light and elevated temperature-induced degradation
 IAM: Incidence angle modifier
 PAN File: PVSyst .pan file
 MSV: Maximum system voltage
 UVID: Ultraviolet induced degradation
 SML: Static mechanical load
 DML: Dynamic mechanical load
 CID: Current included degradation

Characterizations

IV: Flash test at STC
 EL: EL image at Isc
 LIC: Flash test at 200W/m²
 LCEL: EL image at 1/10*Isc
 VI: Visual inspection
 WL: Wet leakage
 Diode: Diode test
 Color: Backsheet color measurement

Note: Not all measurements are taken at each step